

BS EN 62047-11:2013



BSI Standards Publication

Semiconductor devices — Micro-electromechanical devices

Part 11: Test method for coefficients of
linear thermal expansion of free-standing
materials for micro-electromechanical
systems

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National foreword

This British Standard is the UK implementation of EN 62047-11:2013. It is identical to IEC 62047-11:2013.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Published by BSI Standards Limited 2013

ISBN 978 0 580 69448 6

ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 October 2013.

Amendments issued since publication

Date	Text affected
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